



#11/a
01702
J-

PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of

NEW Atty. Dkt. No.: 2775-001

Elwin M. BEATY et al.

OLD Atty. Dkt. No.: 2371

Appln. No.: 09/351,892

Filed: July 13, 1999

Group Art Unit: 2621

Conf. No.: 1396

Examiner: S. Chawan

Title: METHOD AND APPARATUS FOR THREE
DIMENSIONAL INSPECTION OF
ELECTRONIC COMPONENTS

* * * * *
AMENDMENT UNDER 37 C.F.R. § 1.111
* * * * *

RECEIVED
OCT 16 2002
Technology Center 2600

Commissioner for Patents
Washington, D.C. 20231

Dear Sir:

In reply to the Office Action mailed April 11, 2002, please
amend the above-identified patent application as follows:

IN THE CLAIMS:

Amend claim 30 to read as follows:

Sub B6
Q. 30. (Once Amended) A method for three dimensional
inspection of a lead on a part, the method comprising the steps
of:

using a cameral to receive an image of the lead;
transmitting the image of the lead to a frame grabber;
providing fixed optical elements to obtain a side
perspective view of the lead;

Date: October 11, 2002